

# **Description**

The XPX160N03FD uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

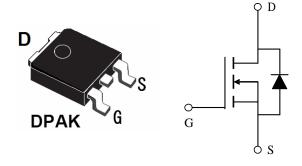
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation

### **Application**

- PWM
- Load Switching



 $V_{DS} = 30V, I_{D} = 160A$   $R_{DS}(ON) = 1.9 m\Omega$  (typ) @  $V_{GS} = 10V$   $R_{DS}(ON) = 2.6 m\Omega$  (typ) @  $V_{GS} = 4.5V$ 



### **Package Marking and Ordering Information**

Product ID	Pack	Marking	Qty(PCS)
XPX150N03FD	TO-252-3L	XPX150N03FD XXXX YYYY	2500

#### Absolute Maximum Ratings (T<sub>C</sub>=25°Cunless otherwise noted)

Symbol	Parameter	Rating	Units	
V <sub>DS</sub>	Drain-Source Voltage	30	V	
Vgs	Gate-Source Voltage	±20	V	
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	160	А	
I <sub>D</sub> @T <sub>C</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1,6</sup>	125	А	
Ірм	IDM Pulsed Drain Current <sup>2</sup> 480		Α	
EAS	Single Pulse Avalanche Energy <sup>3</sup>	258	mJ	
las	Avalanche Current	72.6	Α	
P <sub>D</sub> @T <sub>C</sub> =25°C	Total Power Dissipation <sup>4</sup>	Total Power Dissipation <sup>4</sup> 186		
Тѕтс	Storage Temperature Range	-55 to 175	°C	
TJ	Operating Junction Temperature Range	-55 to 175	°C	
Reja	Thermal Resistance Junction-Ambient <sup>1</sup>	64	°C/W	
Rejc	Thermal Resistance Junction-Case <sup>1</sup>	0.9	°C/W	



## Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit	
BVDSS	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	30	38		V	
∆BVDSS/∆TJ	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA		0.014		V/°C	
RDS(ON)	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =30A		1.9	2.9	mΩ	
TOO(ON)	Static Brain-Gource On-registance	V <sub>GS</sub> =4.5V , I <sub>D</sub> =15A		2.6	3.5	11122	
VGS(th)	Gate Threshold Voltage	$V_{GS}$ = $V_{DS}$ , $I_D$ =250uA	1.2	1.6	2.5	V	
$\triangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	VGS-VDS, ID -230UA		-5		mV/°C	
IDSS	Drain Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1		
1033	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5	uA	
IGSS	Gate-Source Leakage Current	$V_{GS}$ =±20V , $V_{DS}$ =0V	-		±100	nA	
gfs	Forward Transconductance	$V_{DS}$ =5 $V$ , $I_{D}$ =30 $A$		50		S	
R <sub>g</sub>	Gate Resistance	$V_{DS}$ =0V , $V_{GS}$ =0V , f=1MHz		1.7		Ω	
Qg	Total Gate Charge (4.5V)			56.9			
Qgs	Gate-Source Charge	$V_{DS}$ =15V , $V_{GS}$ =10V , $I_{D}$ =15A		13.8		nC	
Qgd	Gate-Drain Charge			23.5			
Td(on)	Turn-On Delay Time		-	20.1			
Tr	Rise Time	$V_{DD}$ =15V , $V_{GS}$ =10V $R_G$ =3.3 $\Omega$ ,		6.3		no	
Td(off)	Turn-Off Delay Time	I <sub>D</sub> =1A	-	124.6		ns	
T <sub>f</sub>	Fall Time			15.8			
Ciss	Input Capacitance			5049			
Coss	Output Capacitance	$V_{DS}$ =15V , $V_{GS}$ =0V , f=1MHz		690		pF	
Crss	Reverse Transfer Capacitance			525			
IS	Continuous Source Current <sup>1,5</sup>	\/-=\/-=0\/			205	Α	
ISM	Pulsed Source Current <sup>2,5</sup>	$V_G=V_D=0V$ , Force Current	-		500	Α	
VSD	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V	

#### Note:

- 1. The data tested by surface mounted on a 1 inch2 FR-4 board with 2OZ copper.
- $2_{\times}$  The data tested by pulsed , pulse width  $\leqq 300 us$  , duty cycle  $\leqq 2\%$
- 3、The EAS data shows Max. rating . The test condition is VDD=25V,VGS=10V,L=0.1Mh,IAS=22A
- 4. The power dissipation is limited by 175°C junction temperature
- 5. The data is theoretically the same as ID and IDM, in real applications, should be limited by total power dissipation.



## **Typical Characteristics**

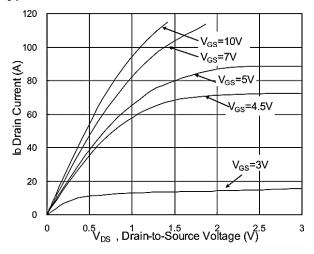


Fig.1 Typical Output Characteristics

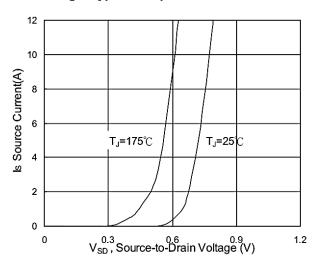


Fig.3 Forward Characteristics of Reverse

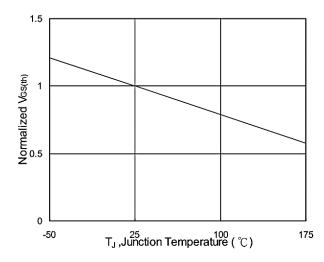


Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$ 

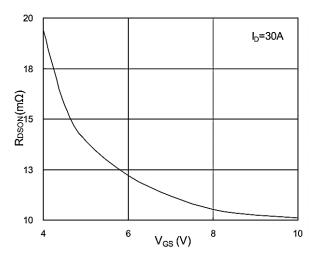


Fig.2 On-Resistance vs. G-S Voltage

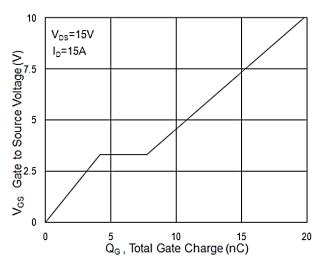


Fig.4 Gate-Charge Characteristics

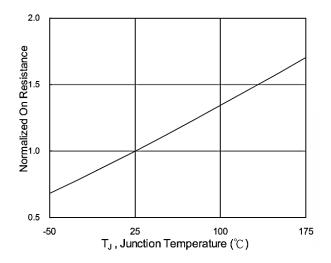
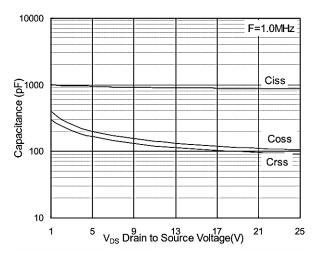


Fig.6 Normalized R<sub>DSON</sub> vs. T<sub>J</sub>





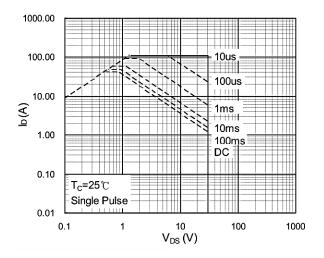


Fig.7 Capacitance

Fig.8 Safe Operating Area

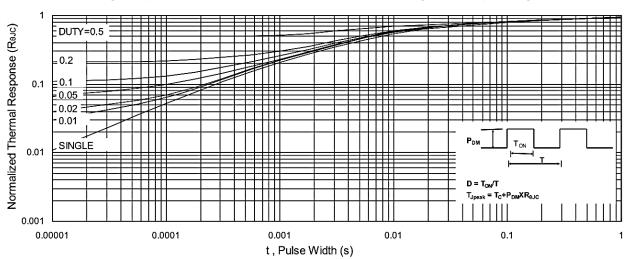


Fig.9 Normalized Maximum Transient Thermal Impedance

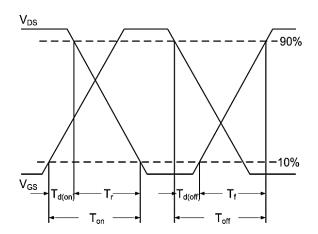


Fig.10 Switching Time Waveform

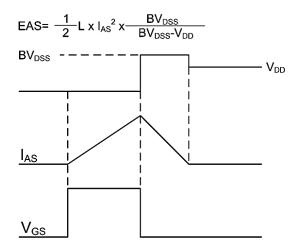
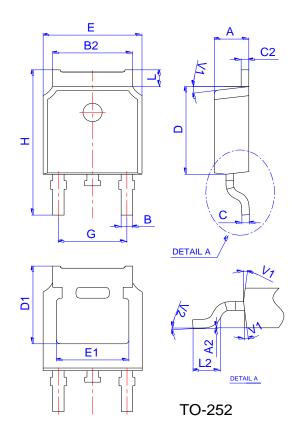


Fig.11 Unclamped Inductive Switching Waveform

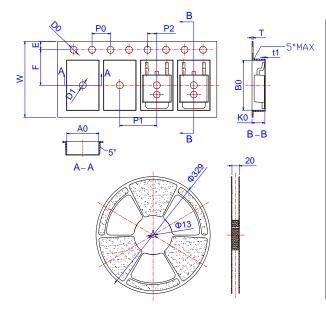


# Package Mechanical Data:TO-252-3L



	Dimensions						
Ref.	. Millin		lillimeters		Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.	
Α	2.10		2.50	0.083		0.098	
A2	0		0.10	0		0.004	
В	0.66		0.86	0.026		0.034	
B2	5.18		5.48	0.202		0.216	
С	0.40		0.60	0.016		0.024	
C2	0.44		0.58	0.017		0.023	
D	5.90		6.30	0.232		0.248	
D1	5.30REF			0.209REF			
E	6.40		6.80	0.252		0.268	
E1	4.63			0.182			
G	4.47		4.67	0.176		0.184	
Н	9.50		10.70	0.374		0.421	
L	1.09		1.21	0.043		0.048	
L2	1.35		1.65	0.053		0.065	
V1		7°			7°		
V2	0°		6°	0°		6°	

# **Reel Spectification-TO-252**



	Dimensions					
Ref.	Millimeters			Inches		
	Min.	Тур.	Max.	Min.	Тур.	Max.
W	15.90	16.00	16.10	0.626	0.630	0.634
E	1.65	1.75	1.85	0.065	0.069	0.073
F	7.40	7.50	7.60	0.291	0.295	0.299
D0	1.40	1.50	1.60	0.055	0.059	0.063
D1	1.40	1.50	1.60	0.055	0.059	0.063
P0	3.90	4.00	4.10	0.154	0.157	0.161
P1	7.90	8.00	8.10	0.311	0.315	0.319
P2	1.90	2.00	2.10	0.075	0.079	0.083
A0	6.85	6.90	7.00	0.270	0.271	0.276
В0	10.45	10.50	10.60	0.411	0.413	0.417
K0	2.68	2.78	2.88	0.105	0.109	0.113
Т	0.24		0.27	0.009		0.011
t1	0.10			0.004		
10P0	39.80	40.00	40.20	1.567	1.575	1.583



#### Flow (wave) soldering (solder dipping)

Product	Peak Temperature	Dipping Time		
Pb device	<b>245</b> ℃ <b>±5</b> ℃	5sec±1sec		
Pb-Free device	260℃+0/-5℃	5sec±1sec		



This integrated circuit can be damaged by ESD UniverChip Corporation recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedure can cause damage. ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

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